

Sheet 1 of 1		FORM PTO 1449 (modified)		ATTY DOCKET NO. 2001-1792A		SERIAL NO. 10/000,304	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Yoko SUZUKI et al.			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE December 4, 2001		GROUP 3652	
Date Submitted to PTO: June 12, 2003							
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
MJC	AA	2001/0011640	Suzuki et al.				
↓	AB	4,967,295	Yamauchi et al.				
MJC	AC	6,436,849	Hasunuma et al.				
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
MJC	AJ	1297882A1	4/2003	EP			
	AK						
	AL						
	AM						
	AN						
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
MJC	AO	Shoko ITO et al., "Wafer ambient control for Agile FAB", 0-7803-6731-6/01/\$10.00*2001 IEEE, pgs. 121-124.					
	AP	<div style="font-size: 1.5em; font-weight: bold; margin: 0;">RECEIVED</div> <div style="font-size: 1.2em; margin: 0;">JUN 16 2003</div> <div style="font-size: 1.5em; font-weight: bold; margin: 0;">GROUP 3600</div>					
	AQ						
EXAMINER M. J. C.		DATE CONSIDERED 10/17/03					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 2

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: July 3, 2002

ATTY DOCKET NO.
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APPLICANT
Yoko SUZUKI et al.

FILING DATE
December 4, 2001

GROUP
3652 1724

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PE	AA	5,345,518	9/1994	Baseman et al.			
AB	AB	6,040,680	3/2000	Toya et al.			
AC	AC	5,380,503	1/95	Fuji et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
AD	AD	2000-174109	6/2000	JP			
AE	AE	9-29020	2/1997	JP			
AF	AF	6-291177	10/1994	JP			
AG	AG	7-94577	4/1995	JP			
AH	AH	617573A		EP			
AI	AI	69401023C		DE			
AJ	AJ	11-195699	7/1999	JP			
AK	AK	2000-223554	8/2000	JP			
AL	AL	11-314703	11/1999	JP			
AM	AM	11-40207	2/1999	JP			
AN	AN	381358B		TW			
AO	AO	0560379A1	9/1993	EP			
AP	AP	6-29373	2/1994	JP			
AQ	AQ	69304570C		DE			
AR	AR	2000-311936	11/2000	JP			

EXAMINER *Winkler* DATE CONSIDERED 06/10/03

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